



Description

Features <ul style="list-style-type: none">• 30V, 40A• $R_{DS(ON)} < 10\text{m}\Omega$ @ $V_{GS} = 10\text{V}$• $R_{DS(ON)} < 17\text{m}\Omega$ @ $V_{GS} = 4.5\text{V}$• Advanced Trench Technology• Provide Excellent $R_{DS(ON)}$ and Low Gate Charge• Lead free product is acquired	Application <ul style="list-style-type: none">• Load Switch• PWM Application• Power management <p><i>100% UIS TESTED!</i> <i>100% ΔV_{ds} TESTED!</i></p>	
 TO-252	 Marking and pin Assignment	 Schematic Diagram

Absolute Maximum Ratings ($T_c=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter		Max.	Units
V_{DSS}	Drain-Source Voltage		30	V
V_{GSS}	Gate-Source Voltage		± 20	V
I_D	Continuous Drain Current	$T_c = 25^\circ\text{C}$	40	A
		$T_c = 100^\circ\text{C}$	20	A
I_{DM}	Pulsed Drain Current ^{note1}		100	A
E_{AS}	Single Pulsed Avalanche Energy ^{note2}		28	mJ
P_D	Power Dissipation	$T_c = 25^\circ\text{C}$	6.2	W
$R_{\theta JC}$	Thermal Resistance, Junction to Case		20	°C/W
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +150	°C



深圳市富满电子集团股份有限公司
SHEN ZHEN FINE MADE ELECTRONICS GROUP CO., LTD.

3040K (文件编号: S&CIC1875) N-channel Enhancement Mode Power MOSFET

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
Off Characteristic						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_D=250\mu\text{A}$	30	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}$, $V_{GS}=0\text{V}$,	-	-	1.0	μA
I_{GSS}	Gate to Body Leakage Current	$V_{DS}=0\text{V}$, $V_{GS}=\pm 20\text{V}$	-	-	± 100	nA
On Characteristics						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$	1.0	1.5	2.5	V
$R_{DS(\text{on})}$ note3	Static Drain-Source on-Resistance	$V_{GS}=10\text{V}$, $I_D=20\text{A}$	-	7.0	10	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}$, $I_D=10\text{A}$	-	11	17	
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS}=15\text{V}$, $V_{GS}=0\text{V}$, $f=1.0\text{MHz}$	-	900	-	pF
C_{oss}	Output Capacitance		-	140	-	pF
C_{rss}	Reverse Transfer Capacitance		-	120	-	pF
Q_g	Total Gate Charge	$V_{DS}=15\text{V}$, $I_D=20\text{A}$, $V_{GS}=10\text{V}$	-	19	-	nC
Q_{gs}	Gate-Source Charge		-	6.3	-	nC
Q_{gd}	Gate-Drain("Miller") Charge		-	4.5	-	nC
Switching Characteristics						
$t_{d(on)}$	Turn-on Delay Time	$V_{DS}=15\text{V}$, $I_D=10\text{A}$, $R_{\text{GEN}}=3\Omega$, $V_{GS}=10\text{V}$	-	6	-	ns
t_r	Turn-on Rise Time		-	5	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	25	-	ns
t_f	Turn-off Fall Time		-	7	-	ns
Drain-Source Diode Characteristics and Maximum Ratings						
I_s	Maximum Continuous Drain to Source Diode Forward Current	-	-	40	-	A
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current	-	-	100	-	A
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS}=0\text{V}$, $I_s=40\text{A}$	-	-	1.2	V
trr	Body Diode Reverse Recovery Time	$I_F=40\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$	-	7	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	6.3	-	nC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

2. EAS condition: $T_J=25^\circ\text{C}$, $V_{GS}=10\text{V}$, $R_G=25\Omega$, $L=0.5\text{mH}$

3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 0.5\%$



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Typical Performance Characteristics

Figure 1: Output Characteristics

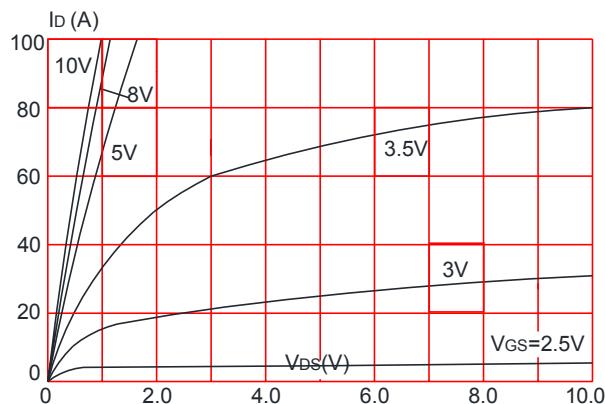


Figure 2: Typical Transfer Characteristics

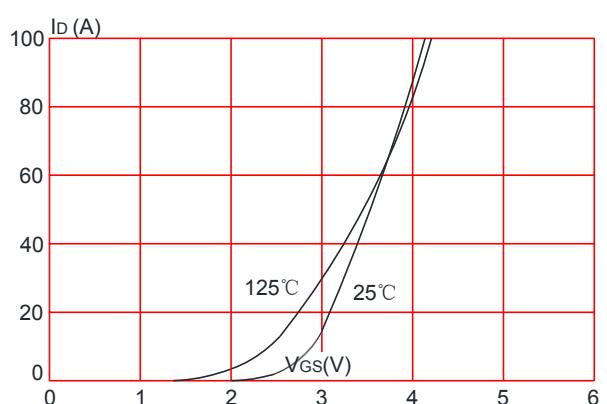


Figure 3: On-resistance vs. Drain Current

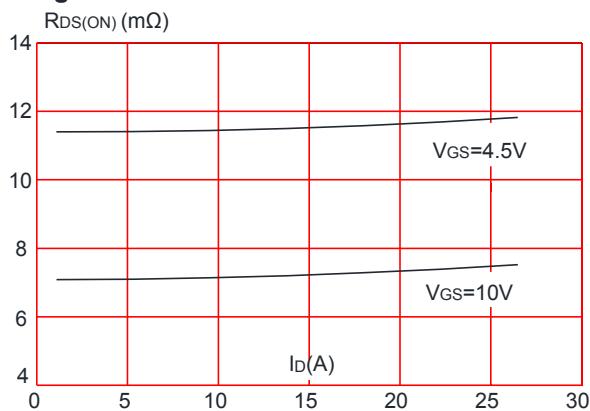


Figure 5: Gate Charge Characteristics

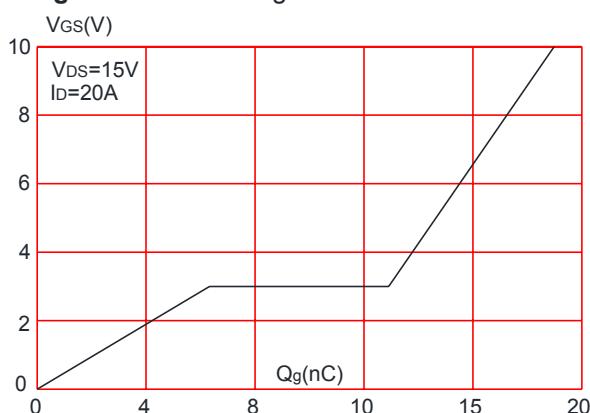


Figure 4: Body Diode Characteristics

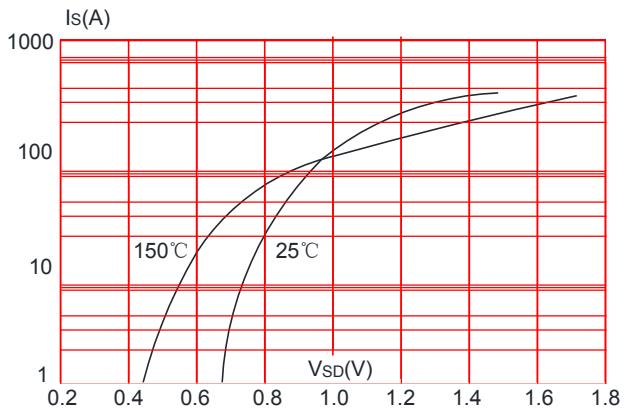


Figure 6: Capacitance Characteristics

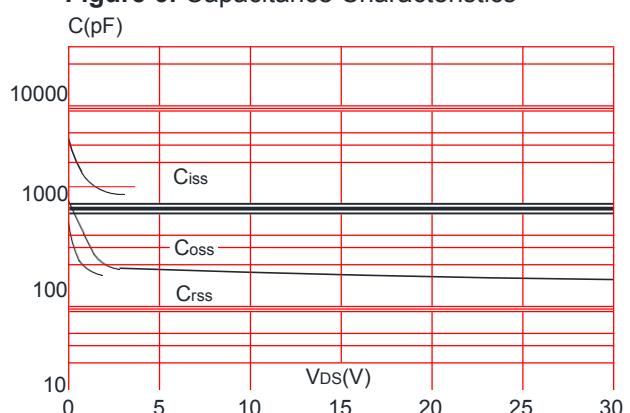




Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

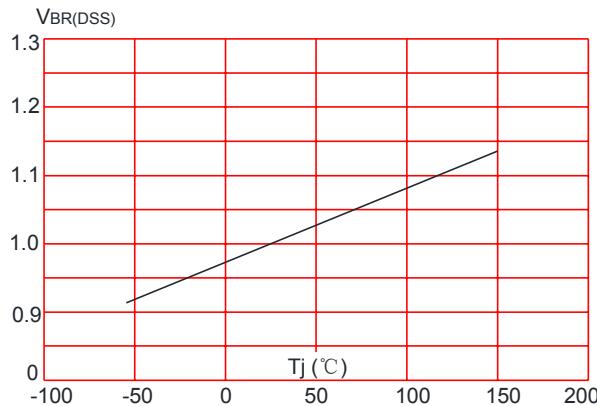


Figure 8: Normalized on Resistance vs. Junction Temperature

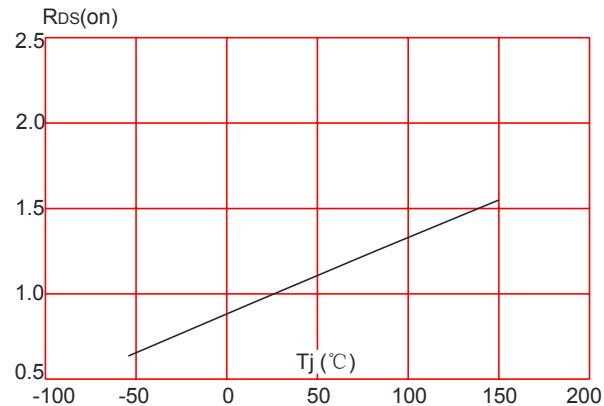


Figure 9: Maximum Safe Operating Area

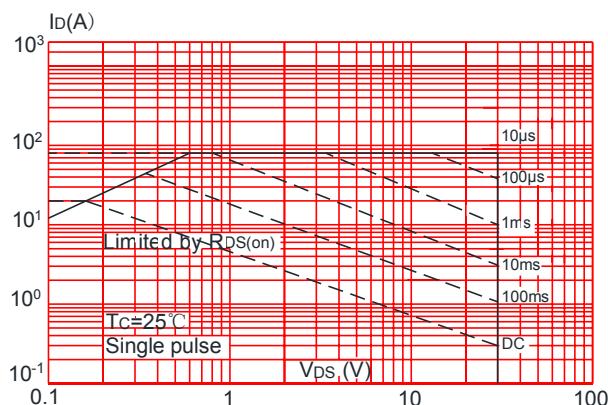


Figure 10: Maximum Continuous Drain Current vs. Case Temperature

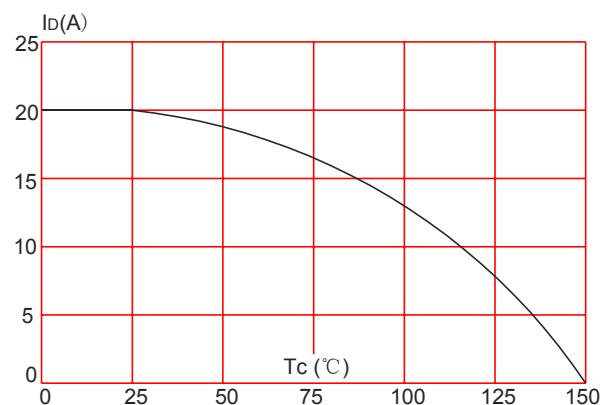
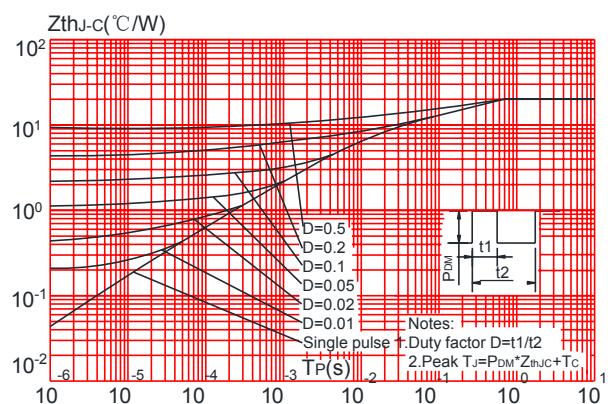


Figure 11: Maximum Effective Transient Thermal Impedance, Junction-to-Case





Test Circuit

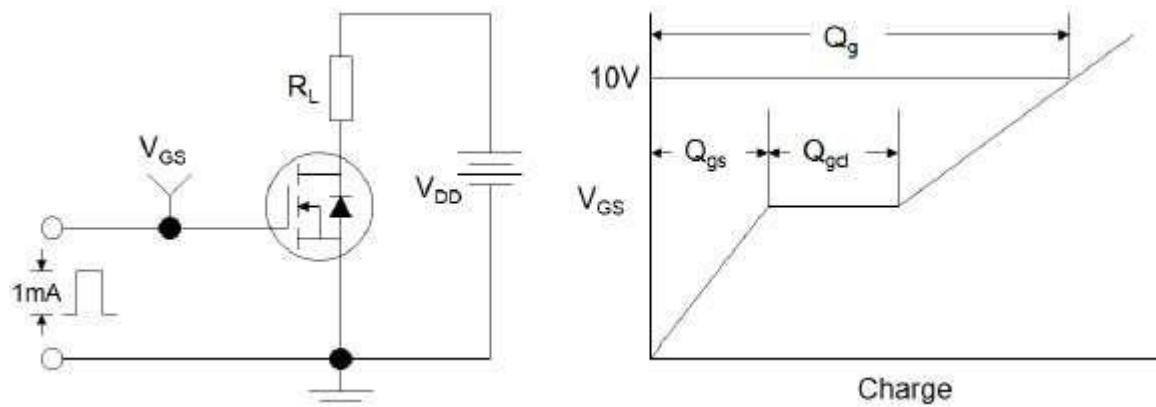


Figure1:Gate Charge Test Circuit & Waveform

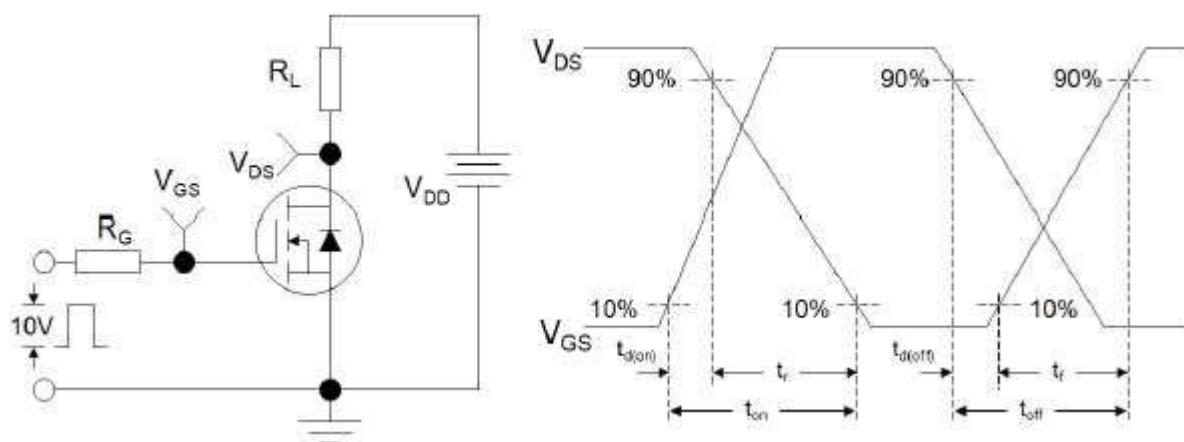


Figure 2: Resistive Switching Test Circuit & Waveforms

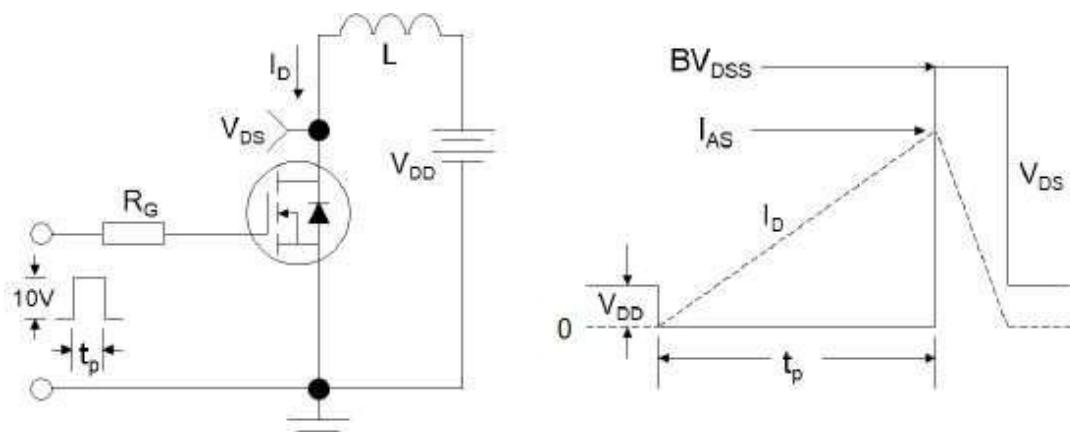
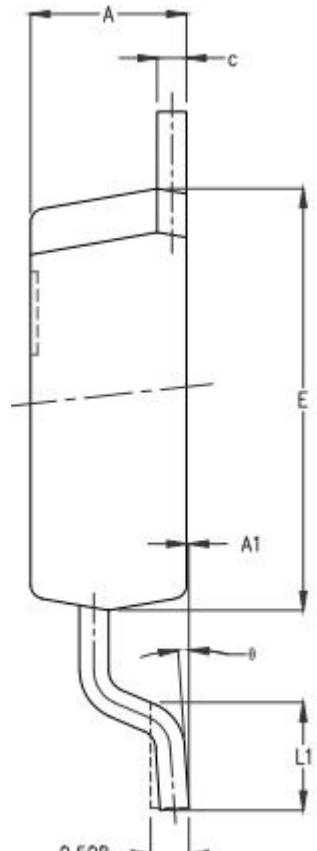
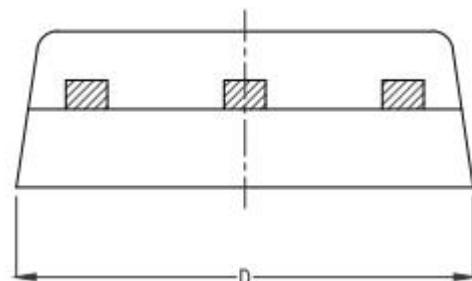
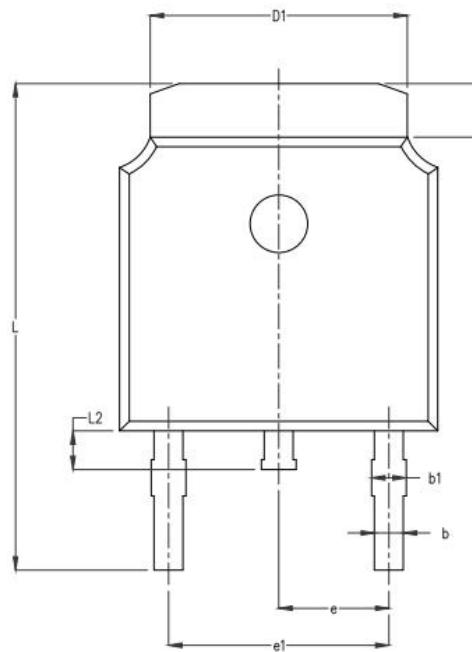


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms



TO-252 Package Information



SYMBOL	MILLIMETER		
	MIN	NOM	MAX
A	2.15	2.25	2.35
A1	0.00	0.06	0.12
B	0.96	1.11	1.26
b	0.59	0.69	0.79
b1	0.69	0.81	0.93
c	0.34	0.42	0.50
D	6.45	6.60	6.75
D1	5.23	5.33	5.43
E	5.95	6.10	6.25
e	2.286TYP.		
e1	4.47	4.57	4.67
L	9.90	10.10	10.30
L1	1.40	1.55	1.70
L2	0.60	0.80	1.00
θ	0°	4°	8°